



phido ligands at the Re atoms are in the *syn* position too, and a crystallographic twofold axis runs through the midpoint of the Re...Re vector. This geometry results in the axial PHCy<sub>2</sub> and CO ligands having intramolecular non-bonding distances of PH...HP 2.32 (15) Å [P—H is 1.44 (8) Å] and O...O 2.994 (15) Å. For a corresponding planar molecule like (I), the carbonyl O...O distances are about 3.2 Å, but the calculated PH...HP separation of 0.9 Å and cyclohexyl CH...HC separation of 1.8 Å would clearly be too short and the resulting repulsive forces give rise to the observed ring distortion. Similar ring folding in order to reduce intramolecular repulsion is also known for  $\mu$ -P-bridged complexes (Flörke & Haupt, 1994). The Re—S bond lengths of 2.523 (2) and 2.526 (2) Å compare well with those of (I), but the Re—S—Re and S—Re—S angles of 98.93 (8) and 74.64 (8)°, respectively, reflect the folding of the ring. The non-bonding Re...Re distance is 3.838 (1) Å.

## Experimental

For the preparation of (I), Re<sub>2</sub>(CO)<sub>10</sub> (200 mg, 0.307 mmol) and 4-methoxy-thiophenol (75  $\mu$ l, 0.612 mmol) were heated at 443 K in a sealed glass tube in the presence of xylene (1.5 ml) for 10 h. Subsequent thin-layer chromatography (TLC) separation (eluant: dichloromethane/*n*-hexane 1/5) gave (I) in 10% yield. Single crystals were grown from chloroform/*n*-pentane. For the preparation of (II), trimethylamine *N*-oxide (17 mg, 0.226 mmol) were added to a solution of Re<sub>2</sub>[ $\mu$ -S(2-naphthyl)]<sub>2</sub>(CO)<sub>8</sub> (100 mg, 0.109 mmol) and PHCy<sub>2</sub> (44  $\mu$ l, 0.218 mmol) in tetrahydrofuran. The Re adduct was prepared according to Treichel & Tegen (1988). After stirring for 2 h, (II) was isolated by TLC separation (eluant: dichloromethane/*n*-hexane 1/2) in 60% yield. Single crystals were grown from dichloromethane/*n*-pentane.

## Compound (I)

### Crystal data

[Re<sub>2</sub>(C<sub>7</sub>H<sub>7</sub>OS)<sub>2</sub>(CO)<sub>8</sub>]  
*M<sub>r</sub>* = 874.85  
 Monoclinic, *P*2<sub>1</sub>/*n*  
*a* = 9.731 (2) Å  
*b* = 9.638 (1) Å  
*c* = 13.772 (1) Å  
 $\beta$  = 107.66 (1)°  
*V* = 1230.8 (3) Å<sup>3</sup>  
*Z* = 2

*D<sub>x</sub>* = 2.361 Mg m<sup>-3</sup>  
 Mo *K* $\alpha$  radiation  
 Cell parameters from 30 reflections  
 $\theta$  = 7.323–22.046°  
 $\mu$  = 10.051 mm<sup>-1</sup>  
*T* = 203 (2) K  
 Block, pale yellow  
 0.44 × 0.24 × 0.18 mm

### Data collection

Siemens *P4* diffractometer  
 2 $\theta$ / $\omega$  scans  
 Absorption correction:  $\psi$  scan  
 (North *et al.*, 1968)  
*T<sub>min</sub>* = 0.080, *T<sub>max</sub>* = 0.164  
 3716 measured reflections  
 2832 independent reflections  
 2448 reflections with *I* > 2 $\sigma$ (*I*)

*R<sub>int</sub>* = 0.019  
 $\theta_{\max}$  = 27.50°  
*h* = -12 → 1  
*k* = -1 → 12  
*l* = -17 → 17  
 3 standard reflections  
 every 397 reflections  
 intensity decay: < 1%

**Table 1**

Selected geometric parameters (Å, °) for (I).

Re1—S1 <sup>i</sup>	2.5179 (12)	S1—C11	1.796 (4)
Re1—S1	2.5243 (12)		
S1 <sup>i</sup> —Re1—S1	81.53 (4)	C11—S1—Re1	114.20 (16)
C11—S1—Re1 <sup>i</sup>	111.92 (16)	Re1 <sup>i</sup> —S1—Re1	98.47 (4)

Symmetry code: (i) -1 - x, 1 - y, -z.

## Refinement

Refinement on *F*<sup>2</sup>  
*R*[*F*<sup>2</sup> > 2 $\sigma$ (*F*<sup>2</sup>)] = 0.026  
*wR*(*F*<sup>2</sup>) = 0.063  
*S* = 1.049  
 2832 reflections  
 165 parameters  
 H-atom parameters constrained

$w = 1/[\sigma^2(F_o^2) + (0.0352P)^2 + 1.1289P]$   
 where  $P = (F_o^2 + 2F_c^2)/3$   
 $(\Delta/\sigma)_{\max} < 0.001$   
 $\Delta\rho_{\max} = 0.991 \text{ e } \text{Å}^{-3}$   
 $\Delta\rho_{\min} = -0.995 \text{ e } \text{Å}^{-3}$   
 Extinction correction: *SHELXTL*  
 (Siemens, 1995a)  
 Extinction coefficient: 0.00201 (18)

## Compound (II)

### Crystal data

[Re<sub>2</sub>(C<sub>12</sub>H<sub>23</sub>P)<sub>2</sub>(C<sub>10</sub>H<sub>7</sub>S)<sub>2</sub>(CO)<sub>6</sub>]  
*M<sub>r</sub>* = 1255.44  
 Monoclinic, *C*2/*c*  
*a* = 24.561 (3) Å  
*b* = 9.378 (3) Å  
*c* = 23.722 (3) Å  
 $\beta$  = 112.63 (1)°  
*V* = 5043.3 (18) Å<sup>3</sup>  
*Z* = 4

*D<sub>x</sub>* = 1.653 Mg m<sup>-3</sup>  
 Mo *K* $\alpha$  radiation  
 Cell parameters from 35 reflections  
 $\theta$  = 8.705–15.577°  
 $\mu$  = 4.988 mm<sup>-1</sup>  
*T* = 293 (2) K  
 Prism, colourless  
 0.41 × 0.10 × 0.08 mm

### Data collection

Siemens *P4* diffractometer  
 $\omega$  scans  
 Absorption correction:  $\psi$  scan  
 (North *et al.*, 1968)  
*T<sub>min</sub>* = 0.482, *T<sub>max</sub>* = 0.671  
 6948 measured reflections  
 5783 independent reflections  
 2766 reflections with *I* > 2 $\sigma$ (*I*)

*R<sub>int</sub>* = 0.037  
 $\theta_{\max}$  = 27.50°  
*h* = -31 → 1  
*k* = -1 → 12  
*l* = -28 → 30  
 3 standard reflections  
 every 397 reflections  
 intensity decay: 3%

## Refinement

Refinement on *F*<sup>2</sup>  
*R*[*F*<sup>2</sup> > 2 $\sigma$ (*F*<sup>2</sup>)] = 0.047  
*wR*(*F*<sup>2</sup>) = 0.117  
*S* = 1.021  
 5783 reflections  
 284 parameters  
 H atoms treated by a mixture of independent and constrained refinement

$w = 1/[\sigma^2(F_o^2) + (0.0328P)^2 + 11.0195P]$   
 where  $P = (F_o^2 + 2F_c^2)/3$   
 $\Delta\rho_{\max} = 0.991 \text{ e } \text{Å}^{-3}$   
 $\Delta\rho_{\min} = -0.501 \text{ e } \text{Å}^{-3}$   
 Extinction correction: *SHELXTL*  
 (Siemens, 1995a)  
 Extinction coefficient: 0.00016 (3)

**Table 2**

Selected geometric parameters (Å, °) for (II).

Re1—P1	2.484 (3)	Re1—S1	2.526 (2)
Re1—S1 <sup>i</sup>	2.523 (2)	S1—C31	1.780 (10)
S1 <sup>i</sup> —Re1—S1	74.64 (8)	C31—S1—Re1	115.7 (3)
C31—S1—Re1 <sup>i</sup>	110.4 (3)	Re1 <sup>i</sup> —S1—Re1	98.93 (8)

Symmetry code: (i) -x, y,  $\frac{1}{2}$  - z.

In (II), H1 on P1 was refined isotropically [P1—H1 1.44 (8) Å], while all other H atoms were constrained and treated as riding atoms.

For both compounds, data collection: *XSCANS* (Siemens, 1995b); cell refinement: *XSCANS*; data reduction: *XSCANS*; program(s) used to solve structure: *SHELXTL* (Siemens, 1995a); program(s) used to refine structure: *SHELXTL*; molecular graphics: *SHELXTL*; software used to prepare material for publication: *SHELXTL*.

Supplementary data for this paper are available from the IUCr electronic archives (Reference: NA1446). Services for accessing these data are described at the back of the journal.

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